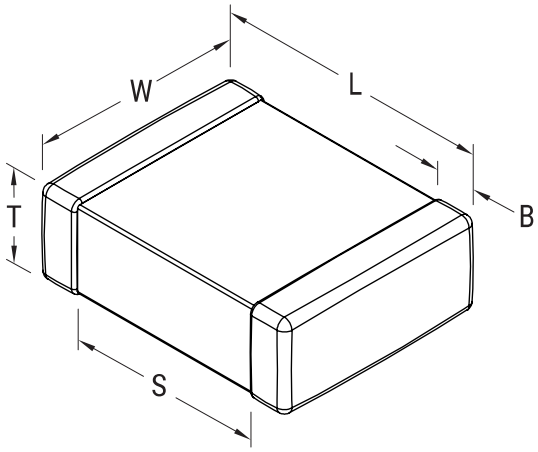
# C0603C153K5RECTU

Aliases (C0603C153K5REC7867)

ESD SMD Comm X7R, Ceramic, 0.015 uF, 10%, 50 VDC, X7R, SMD, MLCC, Temperature Stable, Electro Static Discharge, Class II, 0603 / 1608




Click here for the 3D model.

| General Information | |
|---|---|
| Series | ESD SMD Comm X7R |
| Style | SMD Chip |
| Description | SMD, MLCC, Temperature Stable, Electro Static Discharge, Class II |
| Features | Temperature Stable, Class II |
| RoHS | Yes |
| Termination | Tin |
| Marking | No |
| Typical Component Weight | 4.8 mg |
| Shelf Life | 78 Weeks |
| MSL | 1 |

| Dimensions | |
|---|---|
| L | 1.6mm +/-0.15mm |
| W | 0.8mm +/-0.15mm |
| T | 0.8mm +/-0.07mm |
| S | 0.5mm MIN |
| B | 0.35mm +/-0.15mm |
| Case Code (EIA / mm) | 0603 / 1608 |

| Packaging Specifications | |
|---|---|
| Packaging | T&R, 180mm, Paper Tape |
| Packaging Quantity | 4000 |

| Specifications | |
|---|---|
| Capacitance | 0.015 uF |
| Measurement Condition | 1 kHz 1.0Vrms |
| Tolerance | 10% |
| Voltage DC | 50 VDC |
| ESD Level per AEC-Q200 | 16,000 V ESD Level |
| Dielectric Withstanding Voltage | 125 VDC |
| Temperature Range | -55/+125°C |
| Temp. Coefficient | X7R |
| Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC) | 15%, 1kHz 1.0Vrms |
| Dissipation Factor | 2.5% 1 kHz 1.0Vrms |
| Aging Rate | 3% Loss/Decade Hour: Referee Time is 1000 Hours |
| Insulation Resistance | 66.6667 GOhms |

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